Applicant Initiated Interview Request Form - faxed to: 571. 270. 8538 (pp.)

In re the Application of

Shinichi OKITA

Group Art Unit:

2851

Application No.: 10/594,836

Examiner:

C. RIDDLE

Filed: July 18, 2007

Docket No.:

129559

For:

ALIGNMENT CONDITION DETERMINATION METHOD AND APPARATUS OF THE SAME, AND

EXPOSURE METHOD AND APPARATUS OF THE SAME

							
Tent	ative Participants Brian Kauffman		2) Examiner Riddle	<u> </u>			
(3)		(4	4)			•	
Cont		terview: December 9, 2009		ed Time: 1:30 PM			
Туре (1) [of Interview Req Telephonic	uested: (2) 🔀 Personal	(3) Uideo Conf	erence			
Exhi If yes	bit To Be Shown o , provide brief de	or Demonstrated: YES escription:		⊠ NO			
		Issues	Го Be Discussed				
(Re	Issues j., Obj., etc)	Claims/ Fig. #s	Prior Art	Discussed	Agreed	Not Agreed	
(1)	§102(b)	1, 2, 4-8 and 10-14	US Patent Application Publication No. 2003/0071980 (Ina)				
(2)	§103(a)	9,15,16	US Patent Application Publication No. 2003/0204348 (Suzuki)				
(3) _	<u> </u>		· .			. 🖂	
] C₀	ntinuation Sheet A						
}rief :	Description of Ar	guments to be Presented:					
Noi	ne of the applied re	eferences disclose the sixth and	seventh steps recited i	n claims 7-9			
		icted on the above-identified a					
NOTI	<u>L</u> :						
This f	orm should be com	pleted by applicant and submitte	d to the examiner in ad	ivance of the interv	iew (see MP)	EP 8 713 011	
This a	pplication will not	be delayed from issue because of lvised to file a statement of subst:	annlicantle failure to a				
(App	licant/Applicant's I	Representative Signature)	(Exa	miner/SPE Signati	пе)		